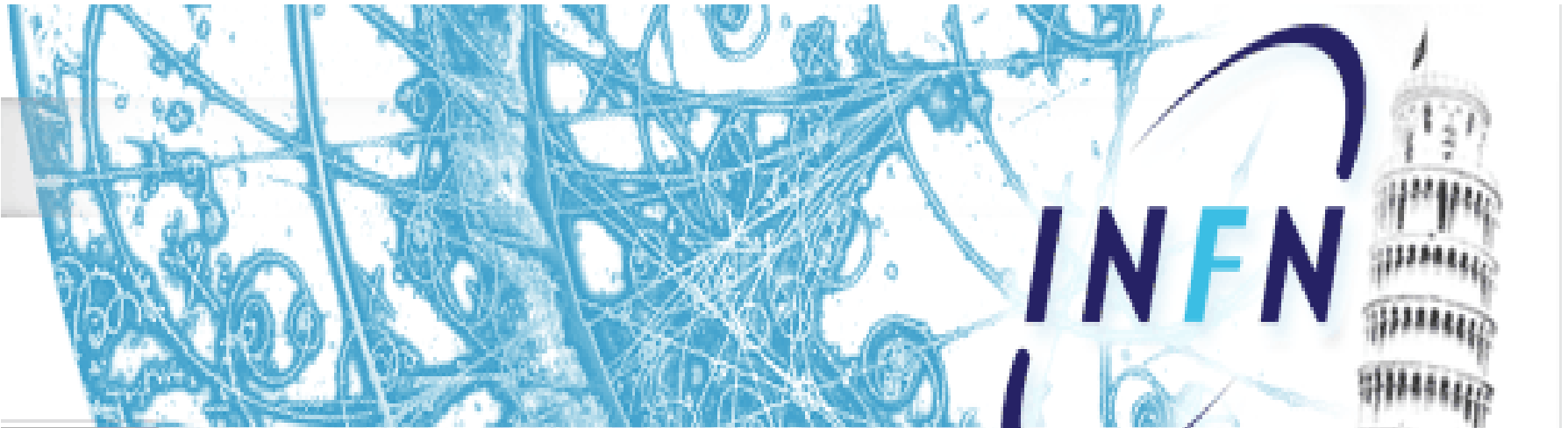


# A guided tour of the construction facilities at the INFN-Pisa

F. Bosi

High-Technology workshop

INFN-Pisa



*Wien – 25-26 April 2013*

# Outline

- The high-technology workshop (7 technicians + 1 Eng.) provides engineering and technological support to the experimental activities of the research groups of the INFN Section in Pisa.

## Main technical activities:

- Development of Solid-State detector: Clean Room(s):
  - Space available for module construction
  - Metrology: manual/automatic CMMs
  - Mechanical/electrical micro-mounting
  - Microbonding
- R&D on cooling: Thermo-Fluid-Dynamic Lab.
  - Thermo-hydraulic test on micro-channels
  - Thermo graphic analysis
  - Climatic chambers
  - In progress set-up for evaporative cooling
- Design of mechanical support: Structural test Lab.
  - Dynamometer for material characterization
  - Vibrational analysis

# Mechanical Engineering Support

Manpower: 1Engineer + 1 designer

Sw available :

- CAD 2D: Autocad 2013
- CAD 3D : Inventor Professional 2013
- FEA sw : ANSYS 2013
- FEA CFD: CFD design 2013
- Industrial solid models database : CADENAS Part Solution

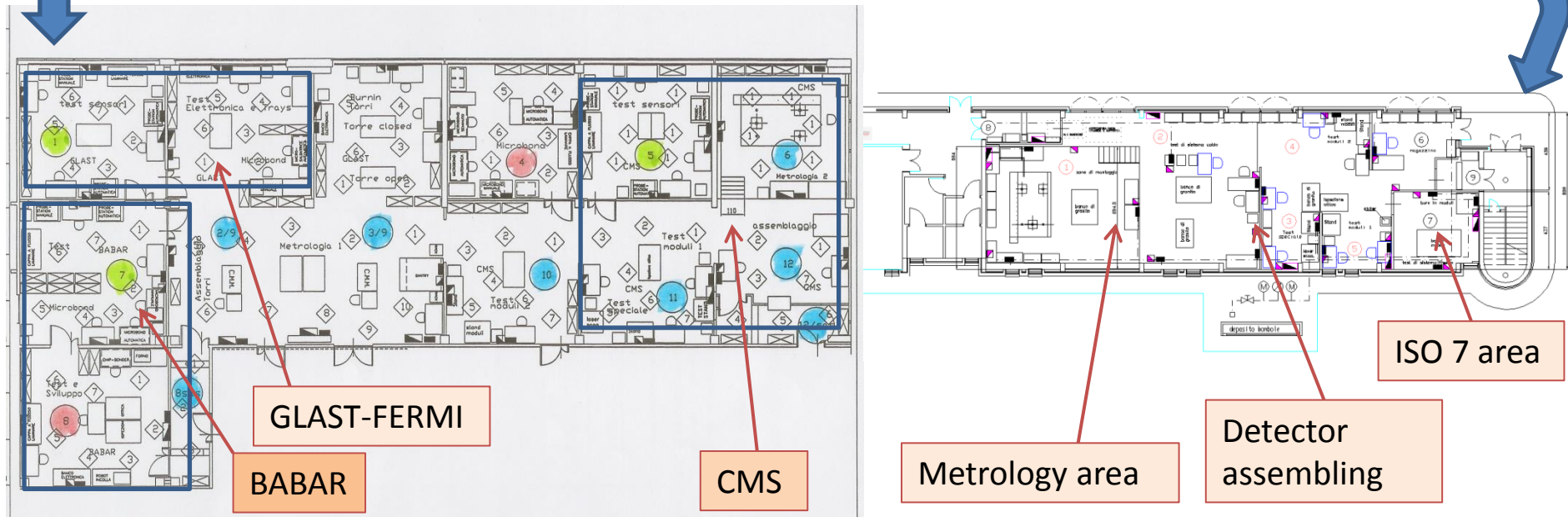
The technical staff matured their expertise in the module construction of the BaBar SVT, the Fermi-Glast LAT, CMS TIB-TID, passing through every steps of the construction of these trackers.

# Clean Rooms

- Historically, in Pisa 3 groups working on Silicon: **BaBar**/Glast-Fermi/CMS
- Two rooms (for each group) dedicated to the electrical characterization of the detectors, with their own instrumentation (probe-stations&Semicon.Analyzer).
- During the construction phase, the acting group uses the central common space facilities.

In Pisa area: 600 m<sup>2</sup> , divided in group-specific and common rooms

In S.Piero a Grado, 8 km far from Pisa, 250 m<sup>2</sup> for large detector assembling



These two Clean Rooms represent the largest INFN Clean Room Laboratories in Italy.

# Clean Rooms

In every cleanroom work space area there are:

- Vacuum and air pressure facilities (8 atm).
- Dry air (dew point  $-40\text{ }^{\circ}\text{C}$ )
- Thermo hygrometric condition are continuously monitored



Clean Room Cleaness Class: 100.000 - Class 10.000 (Federal Standard 209/E)

Temperature :  $21\text{ }^{\circ}\text{C} \pm 1^{\circ}\text{C}$  - Humidity :  $50\% \pm 5\%$

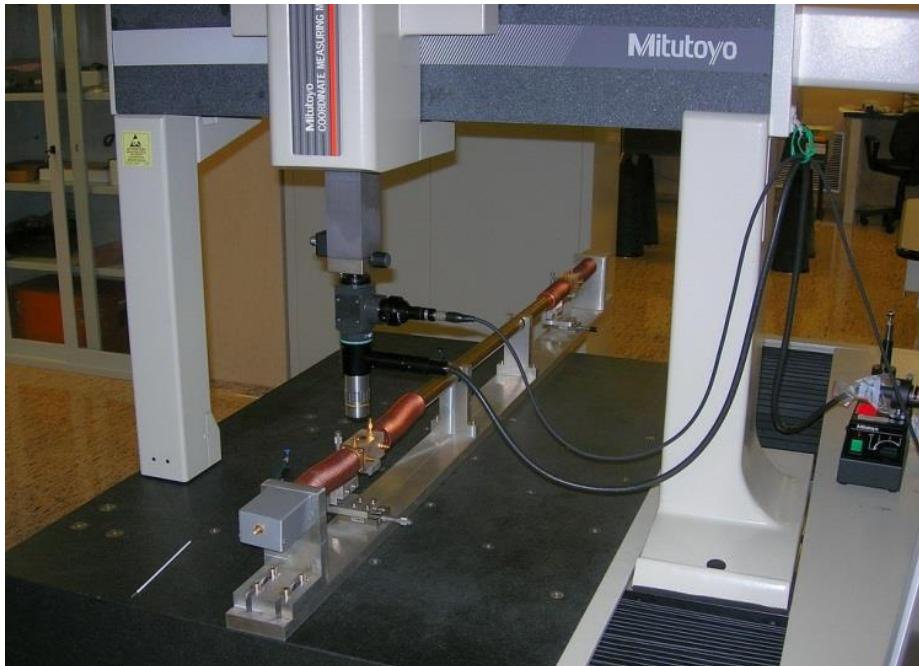
In some little specific working areas (laminar flow cabinet) class 100 can be reached.

Contamination control measurements are systematically performed.

# 3D Metrology

## Coordinate Measuring Machines (with and w/o probe contact):

- Mitutoyo F604 (measured volume 500x600x300 mm<sup>3</sup>)  
Precision 3+4L/1000 um – resolution: 1 um – (semiautomatic)
- Mitutoyo BHN506 (500x600x300mm<sup>3</sup>)  
Precision 3+4L/1000 um – res. 1 um  
CNC controlled – PCDIMIS metrological sw



# 3D Metrology (with and w/o probe contact)

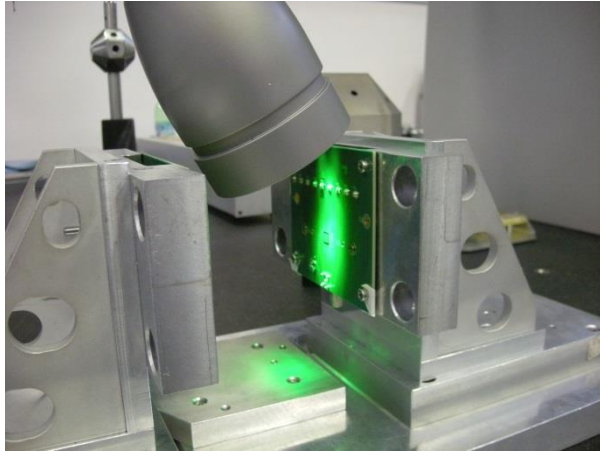
## Coordinate Measuring Machines:

- DEA -Hexagon - Ghibli 26.15.14 (2600x1500x1350mm<sup>3</sup>) (S.Piero Lab)  
Precision 4.5+4L/1000 um – res. 1 um
- DEA Hexagon – Global Image (1500x900x650mm<sup>3</sup>)  
Precision 1.7+3L/1000 um – res. 1 um

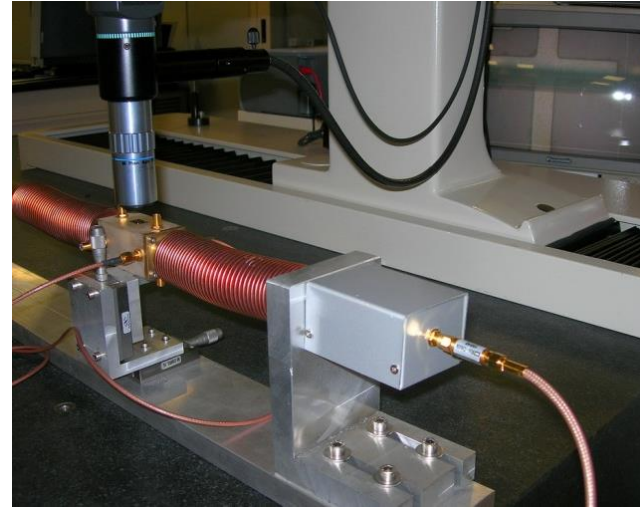
Both the machine are CNC controlled – PCDIMIS metrological sw



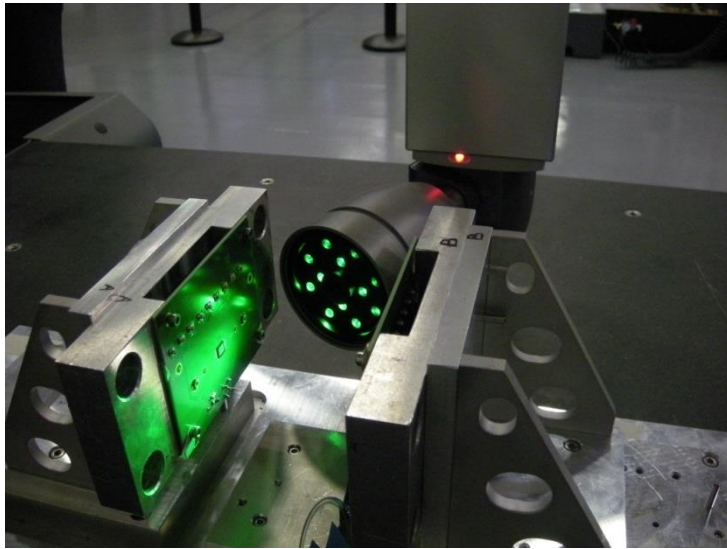
# 3D CMMs



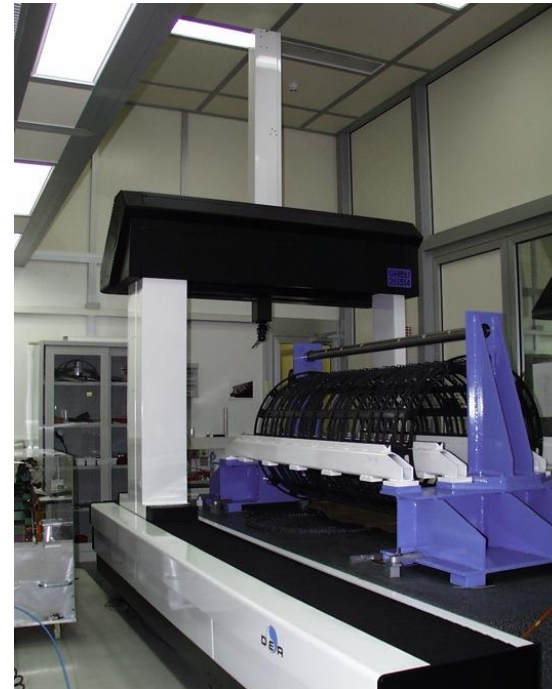
Special laser directional head without contact



Standard vertical optical head without contact



One technician dedicated to metrology.



CMS support tracker structure under measurement on Ghibli 3D CMM (S.Piero Lab)



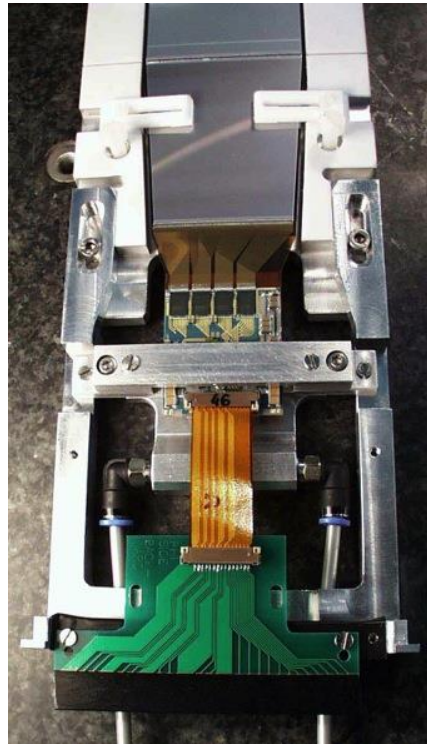
# Mechanical Micromounting

Silicon sensors positioning under CMM for assembling module production

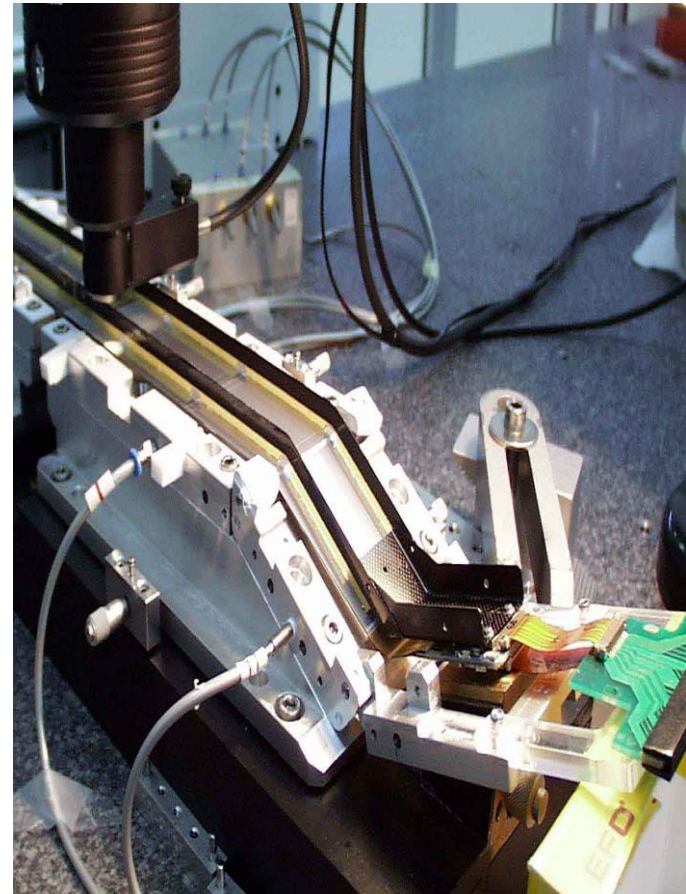
BaBar Si module production



Si module assembly production

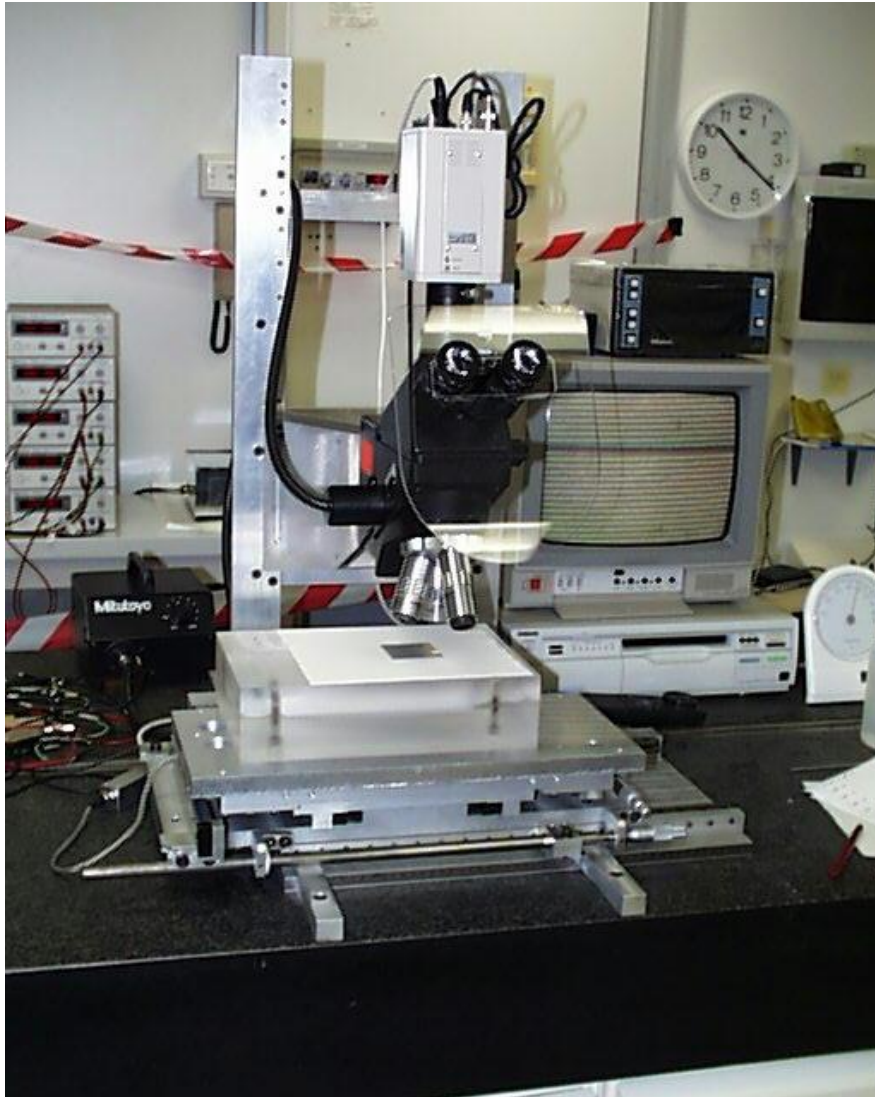


Wedge module before bending



Arch module bent

# Other Lab facilities



Optical inspection bench



FLIP CHIP Bonder KARL  
SUSS FCM 505

# Gluing Machines

I&J Fisnar 750 gluing robot dispensing



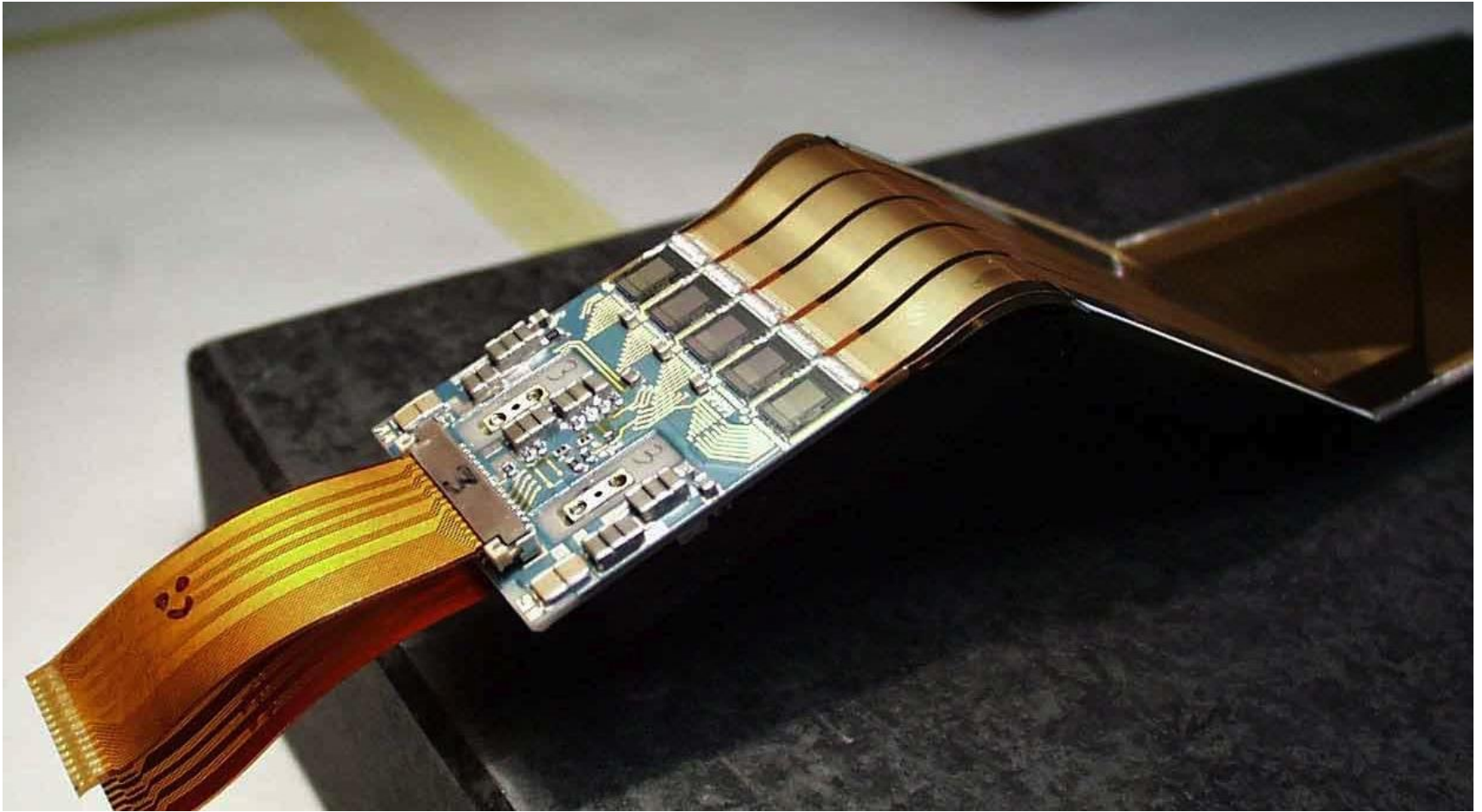
Used for the fanout gluing operations of BaBar Si modules

Die-attach machine Cammax DB 600



Used at cern for the hybrid Die mounting of Totem Si module (adhesive tape)

# FE-Chip loading



Precise positioning of FE chip on ceramic substrates (BaBar ).  
Ovens for conductive glue curing. Possible reworking.

# Microbonding

Manual/semi/automatic deep access bonding machine

Used wire Al 25.4  $\mu\text{m}$  - diameter

One technician dedicated to u-bonding

(+one if needed during production)

K&S 8090 – (CMS)

HUGES 470  
deep-access  
automatic  
(BaBar)



Pull-test  
machine  
DAGE 4000



Manual machine  
K&S 1470



K&S 1470 deep-access  
semiautomatic

# Thermal Environment test

Humidity & temperature test chambers for thermal cycles on (large) detector assembly



Volume test  
1000x1100x1000  
mm<sup>3</sup>  
Temperature range:  
-70°C - +180 °C

Volume test  
3300x3500x2500  
mm<sup>3</sup>  
Temperature range:  
-30°C - +80 °C

Environmental chamber  
Angelantoni Challenge

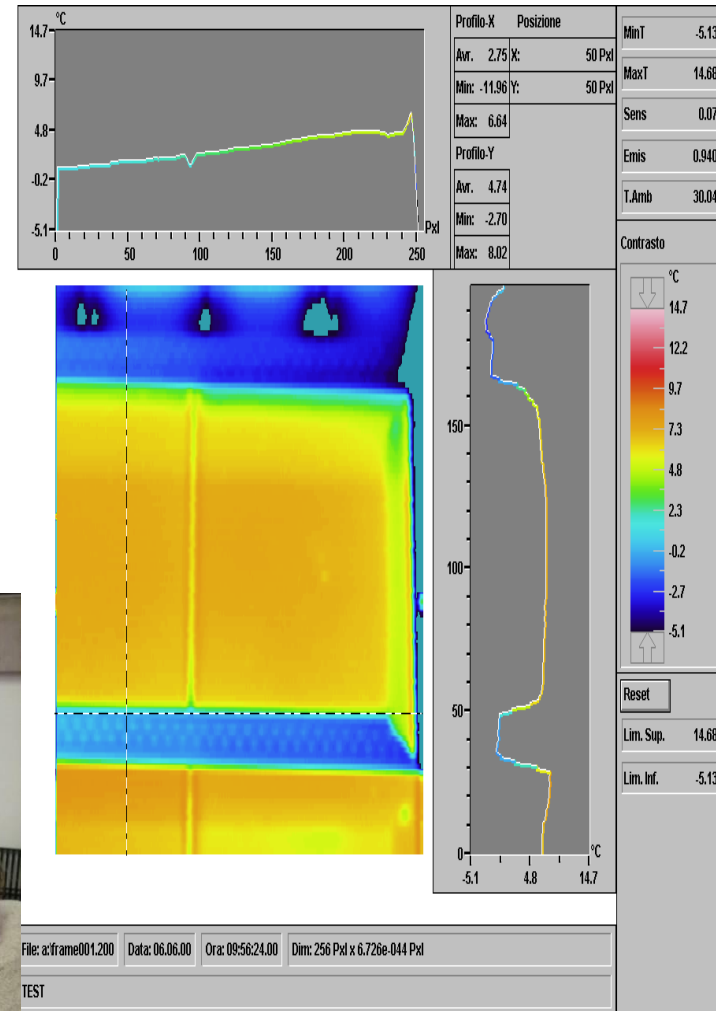


Environmental chamber - S.Piero lab  
Angelantoni WZH30-A1

# Thermography

Temperature measurement by I.R. thermo-camera (AVIO TVS-2000Mk II long wave )

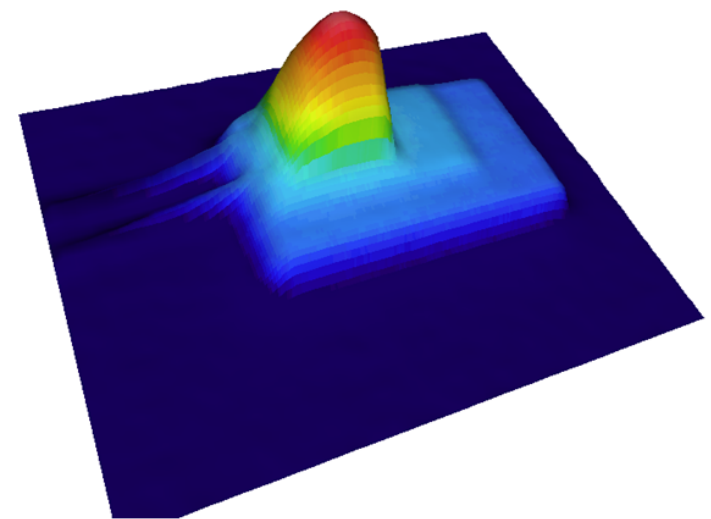
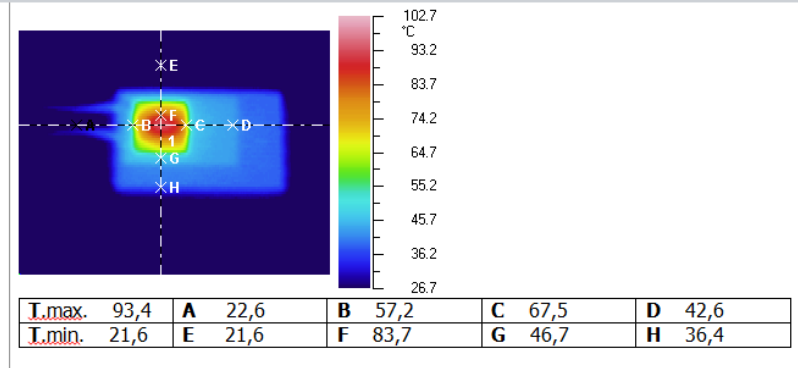
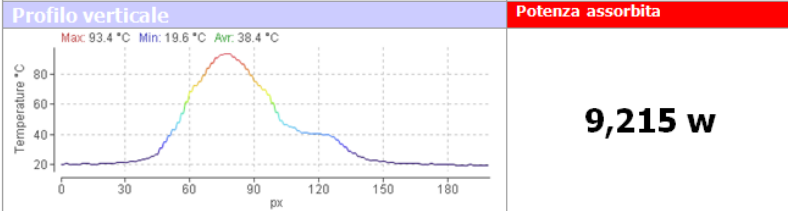
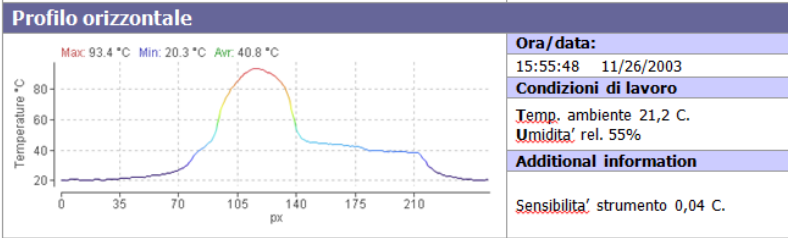
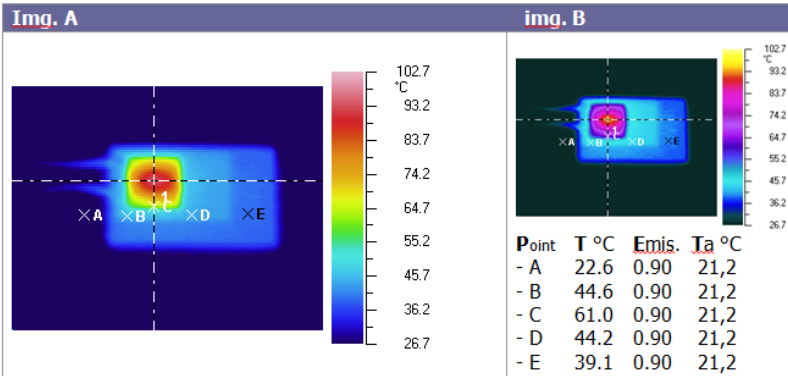
- Resolution: 0.1 °C
- Temperature range: -40/+250 °C
- Experimental thermal analysis on prototypes of cooled read-out electronic for semiconductor detector



# Thermography

**Location** INFN sezione di Pisa  
**Operatore** Mammini Paolo tel. 050 2214228 [paolo.mammini@pi.infn.it](mailto:paolo.mammini@pi.infn.it)  
**Equipment** TVS2000MK-II

- La misura e' stata eseguita in ambiente climatizzato (clean room), laboratorio del servizio **Alte Tecnologie** dell' Istituto Nazionale di Fisica Nucleare di Pisa.  
 L'oggetto in esame e' stato collocato su un supporto a temperatura ambiente ricoperto da un panno ad **emissivita'** nota e riflessione nulla. L'oggetto in esame si presentava interamente ricoperto da un sottile strato di vernice acrilica di colore nero, questo ha consentito di impostare sulla **termocamera** il valore di **emissivita'** = 0,90.  
 L'oggetto e' stato alimentato fino al raggiungimento di 9,215 watt di potenza assorbita. La rilevazione termica e' stata eseguita quando la temperatura e' risultata costante.





# Thermo-Fluid-Dynamic Lab

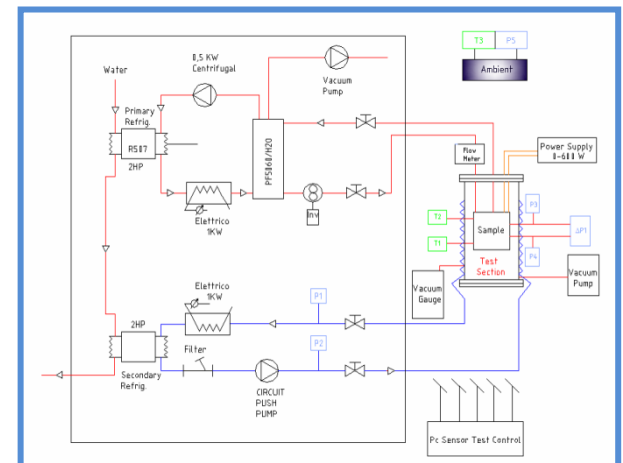
The lab is used for cooling tests and thermal characterization of low mass support structure based on micro-channel technology

- Test bench and chiller for forced convection of liquid monophase



The instrumentation allows to measure/store the values of temp/pressure/flow in the thermal exchange.

Scheme of the Test-bench hydraulic circuit

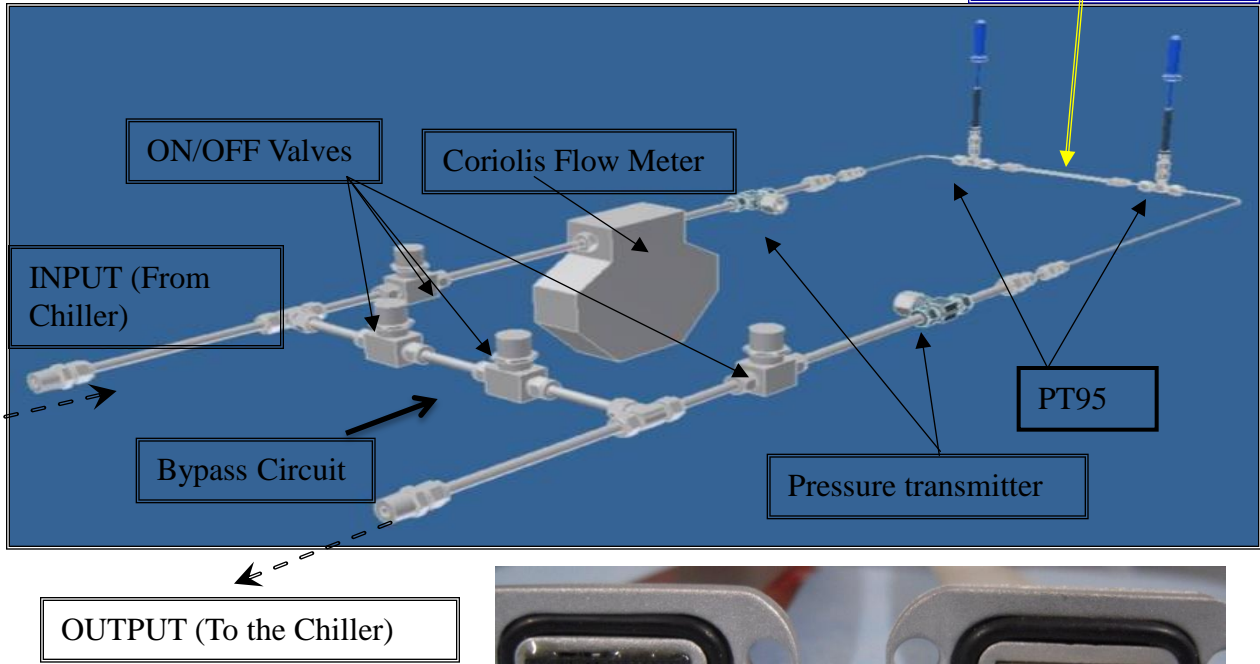


- DAQ HW system (N.24 probe for temperatures, pressure and flow ).
- Chiller dimensioned for a cooling power  $> 1/2$  kW primary and secondary cooling circuit

# Test and set-up at TFD lab

Cooling Circuit Schematic View:

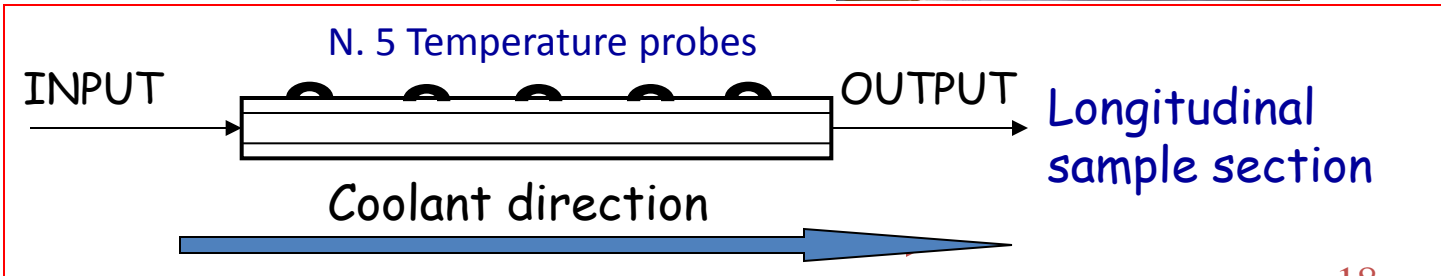
Test Section



DAQ System:



Test Section:

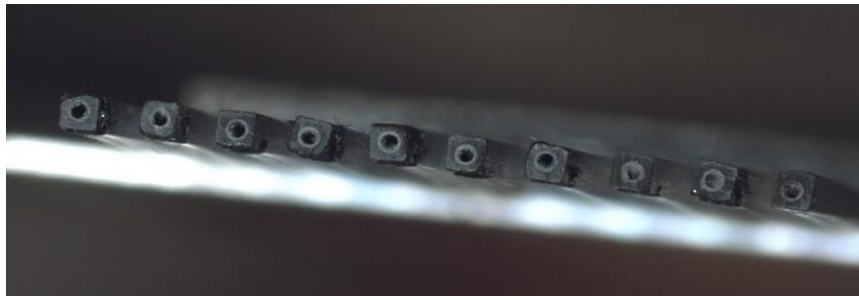
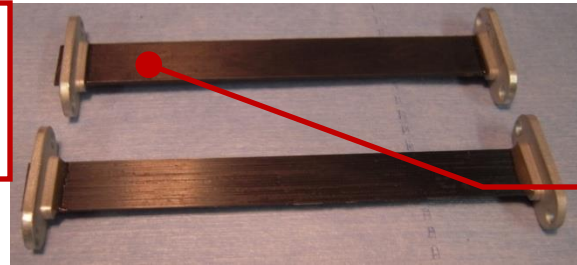
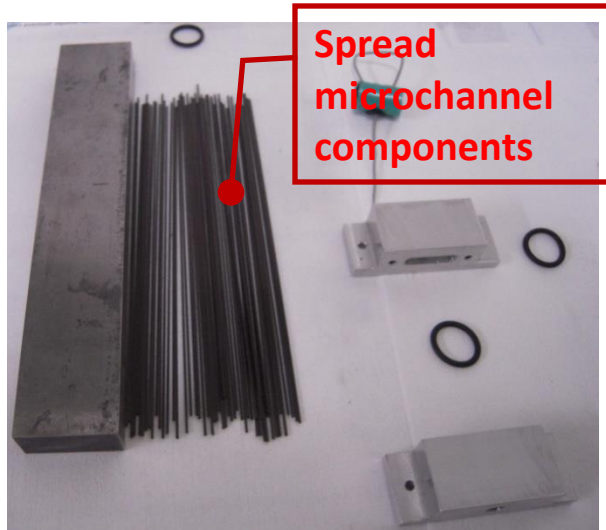
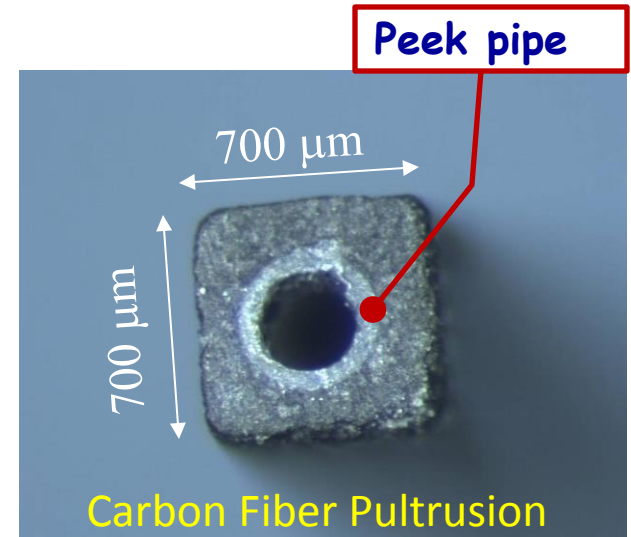
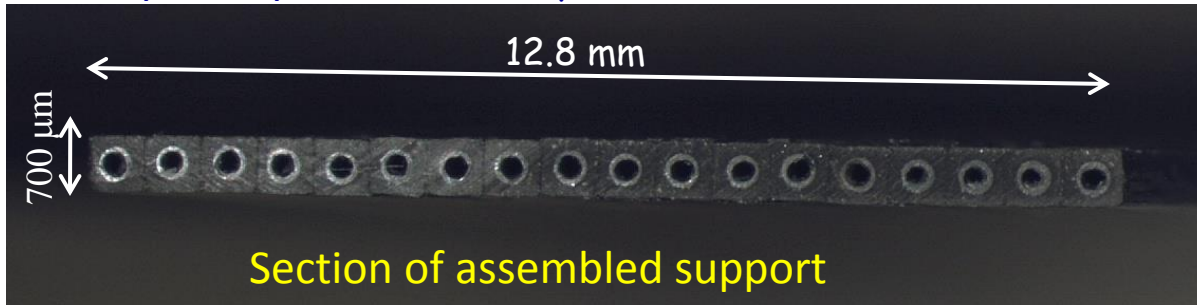


# Module support

## CFRP MICROCHANNEL MODULE

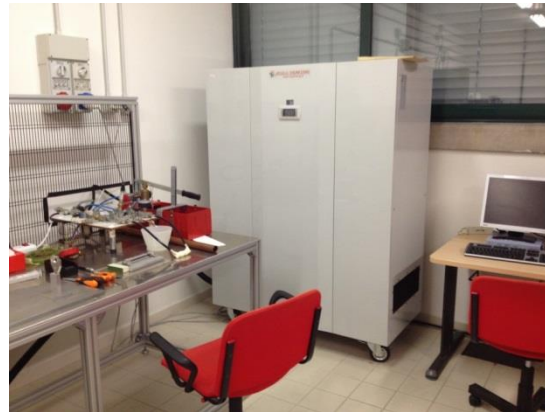
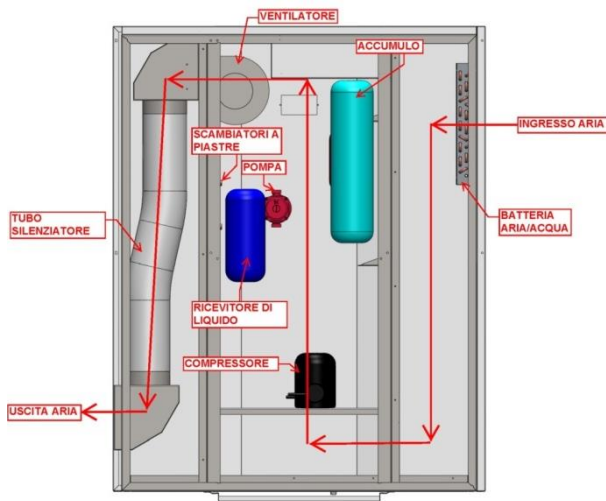
Obtained by pultrusion C.F. TohoTenax HTS 40 , adding and gluing in special masks, side by side, 18 single micro-tube.

The inner diameter of the peek micro-tube is 300  $\mu\text{m}$ , the thickness of the square composite profile is 700  $\mu\text{m}$ .



# Thermo-Fluid-Dynamic Lab.

- Test bench in progress for CO2 facilities evaporative cooling
- Chiller for CO2 production installed

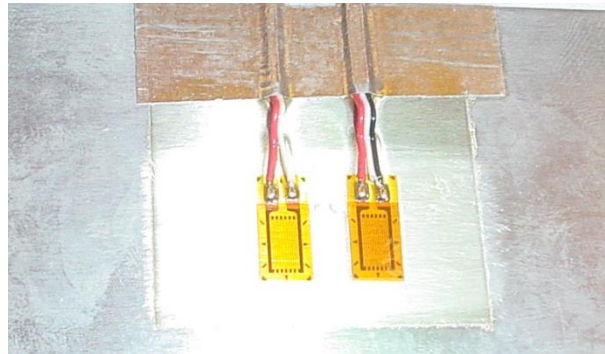
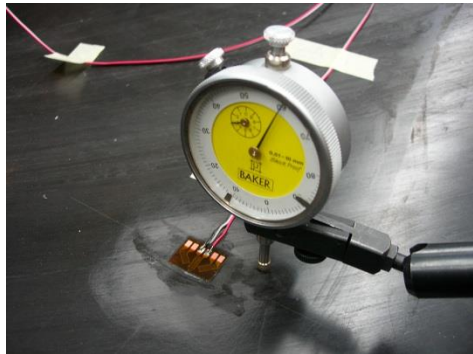


Inlet/outlet pipes  
for test section

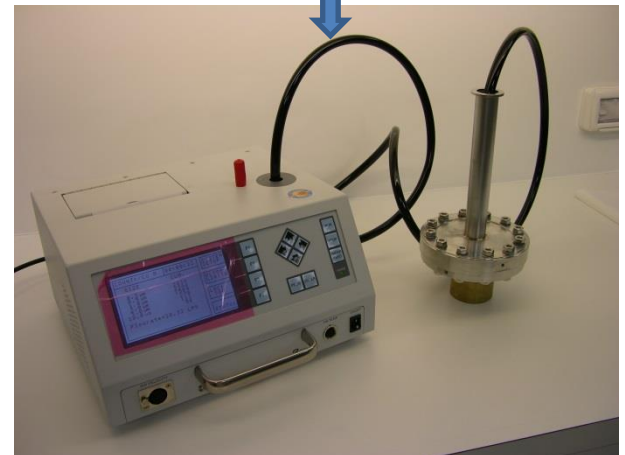
- CO2 Chiller: wide settable range of coolant temperature (-30 °C a +10 °C)
- System circuit control able to set cooling power in the range 16 W - 400 W (antifrost system)
- Coolant flow settable from 0.05 to 1 Kg/min

# Other Lab facilities

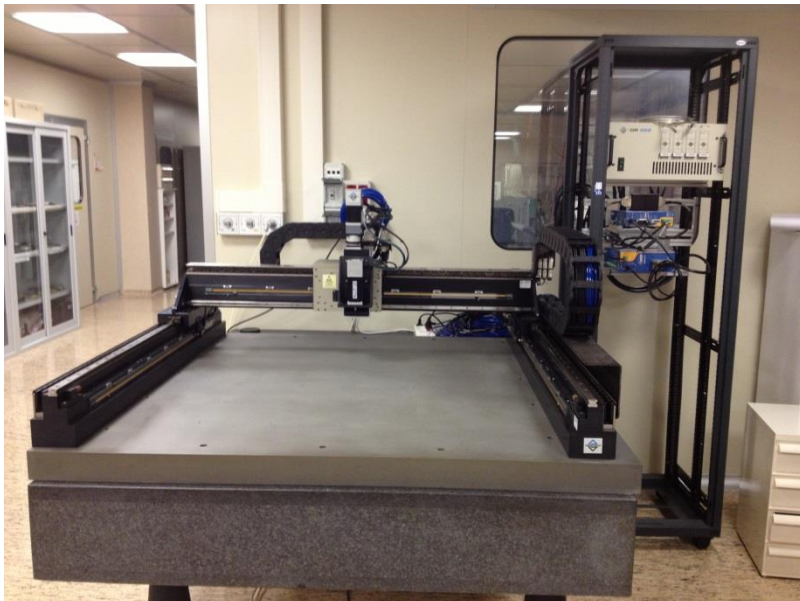
- Stress-Strain Analysis (Strain Gauge)  
Scanner VISHAY with/5 channel  
Portable tester VISHAY 1300 MM



- Contamination control measurement



- Gantry system  
Aerotech  
Working area 1m<sup>2</sup>  
Precision  $\pm 2$   $\mu$ m



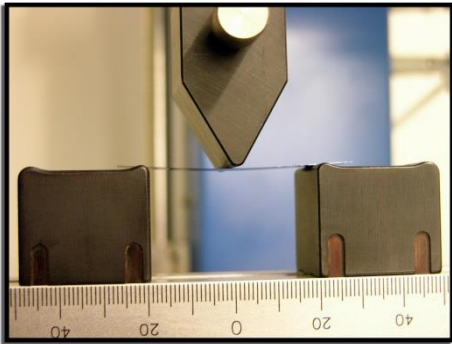
- MET ONE airborne particle counter
- 0.3 micron sensitivity

# Structural test Lab

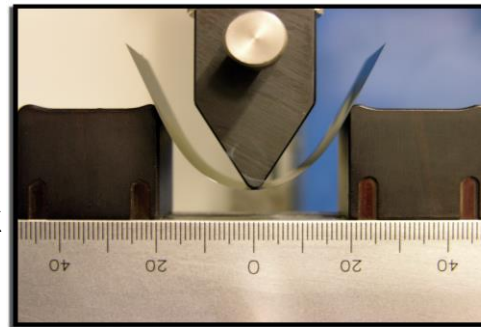
- Mechanical characterization

Materials Testing Machine Lloyd Instruments  
LR50KPlus

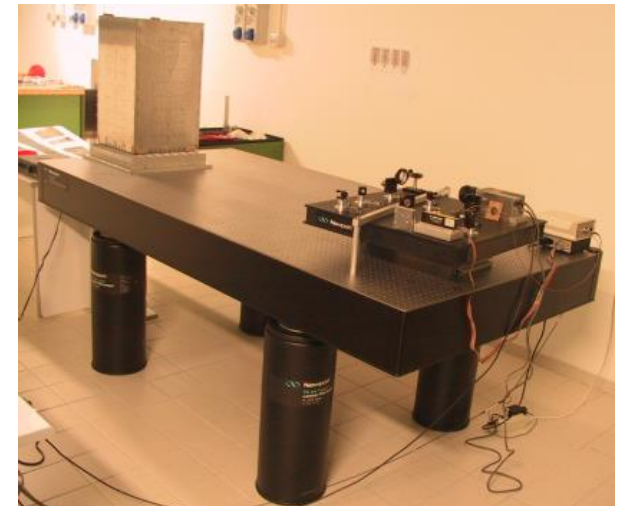
(test up to 50.000 Nw)



Si sample 50 um thick



- Vibrational Analysis  
(Dynamic Shaker up to 10 Kg )



ESPI System (GLAST/FERMI)

# Conclusion

The INFN-Pisa High Technology Workshop can rely on facilities and technical expertise in order to provide the support needed to contribute to the module construction of the BELLE II SVD.